IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Nimmakayala et al. PATENT APPLICATION

Serial No.: Unassigned Group Art Unit: Unassigned Filing Date: Herewith Examiner: Unassigned

For: MAGNIFICATION CORRECTION EMPLOYING OUT-OF-PLANE

DISTORTION OF A SUBSTRATE

INFORMATION DISCLOSURE STATEMENT

Director

for Patents Alexandria, VA 22313

Sir:

The following information is submitted in compliance with Applicants' duty of disclosure under 37 C.F.R. § 1.56. Form PTO-1449 and a copy of each reference recited below accompanies this document. It is respectfully requested that the cited information be expressly considered during the prosecution of this application, and the references be made of record therein and appear among the "references cited" on any patent to issue therefrom.

ISSUED PATENTS

Patent Number 4,724,222

Inventor Feldman Date of Patent 02/09/1988

NON-PATENT DOCUMENTS

Feldman et al. "Wafer Chuck for Magnification correction in X-ray Lithography," Journal of Vacuum Science and Technology, vol. B 16(6), pp. 3476-3479, Nov/Dec 1998.

CERTIFICATE OF MAILING

I hereby certify that this paper (along with any paper referred to as being attached or enclosed) is being deposited with the United States Postal Service with sufficient postage as first class mail in an postage as first class mail in an envelope addressed to: MAIL STOP PATENT APPLICATION, Alexandria, VA 22313-1456
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Respectfully submitted,

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Sheet	1	of	2	Attorney Docket Number	MII-94-69v18	

				U.S. PATENT DOCUMEN	TS	
Examiner nitials*	Cite No.1	U.S. Patent Do	Kind Code ² (if known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant
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¹Unique citation designation number. ²See attached Kinds of U.S. Patent Documents. ³Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶Applicant is to place a check mark here if English language Translation is attached.

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OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS						
Examiner Initials*	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.				
	40	Feldman et al., "Wafer Chuck for Magnification correction in X-ray Lithography," Journal of Vacuum Science				
	A2 and Technology, Nov/Dec 1998, pp. 3476-3479, vol. B 16(6).					
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